



SIM REGIONAL EARLY CAREER METROLOGIST PAPER COMPETITION 2021 - TERMS OF REFERENCE

SCOPE:

To sponsor a technical paper competition for early career metrologists in each of the SIM subregions.

The competition is aimed at:

- encouraging early career professionals in the field of metrology to introduce their scientific work to the metrology community at-large
- introducing one's technical work to colleagues of other NMIs within the SIM Region
- publishing the papers in the NCSLI Conference proceedings and Metrologist Worldwide News, supporting and encouraging early career metrologists who contribute to the development of their NMI

This competition is coordinated by the SIM Professional Development Coordinator with support by SIM Secretariat. Subregional coordinators will cooperate with the communication of the competition within their regions promoting the participation of the NMIs.

AWARDS:

• The winners of the first-place paper from each sub-region will have the opportunity to participate at the NCSLI Workshop & Symposium 2021 if this is their intention and this is supported by SIM Council taking into account COVID pandemic situation.

The NCSL International 2021 Workshop & Symposium will take place August 21-26, 2021. In the case in which in-person participation is agreed, expenses (air fare, lodging, per diem and Conference inscription) will be covered though a NIST grant to NCSLI

First place papers will also be published in the 2021 Conference proceedings.

• The winners of the second-place paper from each SIM subregion will be invited to prepare a poster for presentation at NCSLI, however no travel support will be provided for participation

DEFINITION:

Early Career Metrologists, in the context of this competition, are people who have been employed as a metrologist by a SIM NMI/ DI member of SIM, from no earlier than 2016.

As there are various forms of such employment, the NMI or DI representative shall declare that the applicant is an early career professional and that the NMI support his/her application.

PARTICIPATION:

Early Career Metrologists who want to participate in the competition must send an abstract of their paper (about 500 WORDS) related to any field of metrology, and a copy of their CV to SIM Professional





Development Coordinator (PDC), Rodrigo Costa-Félix (mail: rpfelix@inmetro.gov.br), copying the SIM Secretariat (mail: secretariat.sim.org@gmail.com).

All submitted abstracts will be sent to a "Review Panel" who will evaluate the abstracts and SIM will communicate to the participants the abstract acceptance trough the SIM PDC and the SIM Executive Secretary.

For those abstracts that are accepted by the "Review Panel", full manuscripts should be submitted to the PDC and the SIM Executive Secretary for final evaluation. These manuscripts must not be longer than 4000 words and should include:

- statement of the problem addressed in the general form and its connection with important scientific or practical task
- analysis of the ways of solving the problem
- determination of the way of solving the general problem
- presentation of the main research material with explanation of the obtained results
- conclusions

For more information check the Document "Criteria for early career metrologist competition manuscripts"

REVIEW PANEL:

The "Review Panel" is made up of the SIM Professional Development Coordinator, SIM Technical Committee Chair and vice chair, SIM Project Coordinator and SIM executive secretary. The panel can ask an expert from the Technical Committee to assist in the evaluation.

Manuscripts will be evaluated by the Review Panel to select up to two papers from each of the SIM subregions. A first and second place winners are expected to be selected from each sub-region.

DEADLINE:

Abstract's presentation: April 11, 2021

Abstract's selection: April 19, 2021

Submission of manuscripts: May 19, 2021

Review Panel selection of best papers: June 15, 2021

CONTACT PERSON FOR SIM

Claudia Santo, SIM Executive Secretary

secretariat@sim-metrologia.org

secretariat.sim.org@gmail.com